Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/752,642	NAKAMURA ET AL.
	Examiner	**Art Unit**
	CHRIS C. CHU	2815

SEARCHED

Class	Subclass	Date	Examiner
257	E21.584, E21.582 & E21.174	1/26/2009	C.C.
257	758 & 751	1/26/2009	C.C.
257	762 & 763	1/26/2009	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	1/26/2009	C.C.